

Erratum

Erratum to “Precision interferometric surface metrology of transparent thin film using wavelength tuning” [31 (11) (2017) 5423~5428]Yangjin Kim^{*}*School of Mechanical Engineering, Pusan National University, Busan 46241, Korea*

There is one correction to make to the original article.

Acknowledgement was published incorrectly. The acknowledgement should be corrected as follows

Acknowledgement

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